# Tire Pressure Monitoring Sensor Temperature Compensated and Calibrated, Fully Integrated, Digital Output

#### **GENERAL DESCRIPTION**

The Motorola MPXY8020A is an 8-pin tire monitoring sensor which is comprised of a variable capacitance pressure sensing element, a temperature sensing element, and an interface circuit (with a wake-up feature) all on a single chip. It is housed in a Super-Small Outline Package (SSOP), which includes a media protection filter. Specifically designed for the low power consumption requirements of tire pressure monitoring systems, it can combine with a Motorola remote keyless entry (RKE) system to facilitate a low-cost highly integrated system.

#### **Detailed Description**

The block diagram of the MPXY8020A is shown in Figure 1. The pressure sensor is a capacitive transducer constructed using surface micromachining, the temperature sensor is constructed using a diffused resistor, and the interface circuit is integrated onto the same die as the sensors using a standard silicon CMOS process.

The conditioning of the pressure signal begins with a capacitance to voltage conversion (C to V) followed by a switched capacitor amplifier. This amplifier has adjustable offset and gain trimming. The offset and gain are factory calibrated, with calibration values stored in the EEPROM trim register. This amplifier also has temperature compensation circuits for both sensitivity and offset, which also are factory—adjusted using the EEPROM trim register.

The pressure is monitored by a voltage comparator, which compares the measured value against an 8-bit threshold adjusted by a serial input. By adjusting the threshold and monitoring the state of the OUT pin the external device can check whether a low-pressure threshold has been crossed, or perform up to 8-bit A/D conversions.

The temperature is measured by a diffused resistor with a positive temperature coefficient driven by a current source, thereby creating a voltage. The room temperature value of this voltage is factory–calibrated using the EEPROM trim register. A two–channel multiplexer can route either the pressure or temperature signal to a sampling capacitor that is monitored by a voltage comparator with variable threshold adjust, providing a digital output for temperature.

An internal low frequency, low power 5.4 kHz oscillator with a 14–stage divider provides a periodic pulse to the OUT pin (divide by 16384 for 3 seconds). This pulse can be used to wake up an external MCU to begin an interface with the device. An additional 10–stage divider will provide a pulse every 52 minutes which can be used to reset an external MCU.

The power consumption can be controlled by several operational modes selected by external pins.

## MPXY8020A

TIRE PRESSURE MONITORING SENSOR OPTIMIZED FOR 250 kPa – 450 kPa



SUPER SMALL OUTLINE PACKAGE CASE 1352

ORDERING INFORMATION						
Shipped in Rails Shipped in Tape & Ree						
MPXY8020A6U	MPXY8020A6T1					





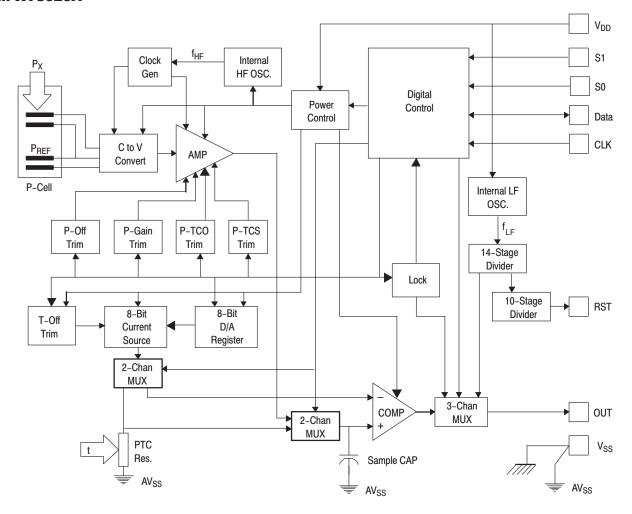
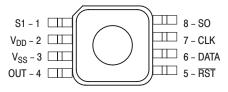


Figure 1. MPXY8020A Block Diagram

## **Package Pinout**

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The pinout for this 8-pin SSOP device is shown in Figure 2.



8-pin Super Small Outline Package (SSOP)

Figure 2. MPXY8020A Device Pinout

#### **Operating Modes**

The device has several operating modes dependent on the applied voltages to the S1 and S0 pins as shown in Table 1. In all the modes listed the channel multiplexers, D/A Register, LFO, and the output pulse dividers will always be powered up as long as there is a voltage source connected to the  $V_{DD}$  pin.

When only the S0 pin is at a logic one the pressure measuring circuit in the device is powered up and the pressure output signal is connected to the sample capacitor through a multiplexer. When the S0 pin returns to the low state the multiplexer will first turn off to store the signal on the sample capacitor before powering down the measuring circuitry.

When only the S1 pin is at a logic one the temperature measuring circuit in the device is powered up and the temperature output signal is connected to the sample capacitor through a multiplexer. When the S1 pin returns to the low state the multiplexer will first turn off to store the signal on the

sample capacitor before powering down the measuring circuitry.

NOTE: All of the EEPROM trim bits will be powered up regardless of whether the pressure or temperature measuring circuitry is activated.

NOTE: If the voltage on the S1 pin exceeds 2.5 times the voltage on the  $V_{DD}$  pin the device will be placed into its Trim/ Test Mode.

NOTE: If the  $V_{DD}$  supply source is switched off in order to reduce current consumption, it is important that all input pins be driven LOW to avoid powering up the device.

If any input pin (S1, S0, DATA, or CLK) is driven HIGH while the  $V_{DD}$  supply is switched off, the device may be powered up through an ESD protection diode. In such a case, the effective  $V_{DD}$  voltage will be about 0.3 V less than the voltage applied to the input pin, and the full device  $I_{DD}$  current will be drawn from the device driving input.

S1	S0	Operating Mode	Pressure Measure System	Temp Measure System	A/D Output Comp.	LFO Oscill.	Serial Data Counter
0	0	Standby/Reset	OFF	OFF	OFF	ON	ACTIVE
0	1	Measure Pressure	ON	OFF	OFF	ON	RESET
1	0	Measure Temperature	OFF	ON	OFF	ON	RESET
1	1	Output Read	OFF	OFF	ON	ON	ACTIVE

**Table 1. Operating Modes** 

#### **Pin Functions**

The following paragraphs give a description of the general function of each pin.

## V<sub>DD</sub> and V<sub>SS</sub> Pins

Power is supplied to the control IC through  $V_{DD}$  and  $V_{SS}$ .  $V_{DD}$  is the positive supply and  $V_{SS}$  is the digital and analog

ground. The control IC operates from a single power supply. Therefore, the conductors to the power supply should be connected to the  $V_{DD}$  and  $V_{SS}$  pins and locally decoupled as shown in Figure 3.

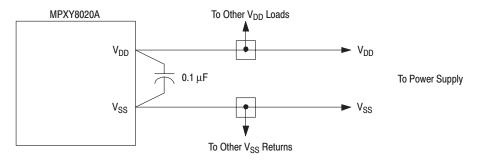


Figure 3. Recommended Power Supply Connections

#### **OUT Pin**

The OUT pin normally provides a digital signal related to the voltage applied to the voltage comparator and the threshold level shifted into an 8-bit register from an external device. When the device is placed in the standby mode the OUT pin is driven high and will be clocked low when an overflow is detected from a clock divider (divide by 16384) driven by the LFO. This allows the OUT pin to wake up an external device such as an MCU.

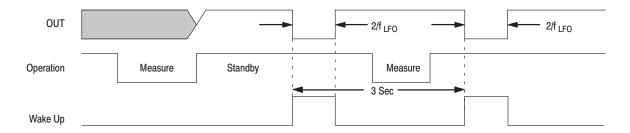


Figure 4. Pulse on OUT Pin During Standby Mode

#### RST Pin

The  $\overline{RST}$  pin is normally driven high and will be clocked low when an overflow is detected from total clock divider (divide by 16,777,216) driven by the LFO. This allows the  $\overline{RST}$  pin to reset an external device such as an MCU. This pulse will appear on the  $\overline{RST}$  pin approximately every 52 minutes

regardless of the operating mode of the device. The pulse lasts for two cycles of the LFO oscillator as shown in Figure 5. Since the  $\overline{RST}$  pin is clocked from the same divider string as the OUT pin, there will also be a pulse on the OUT pin when the  $\overline{RST}$  pin pulses every 52 minutes.

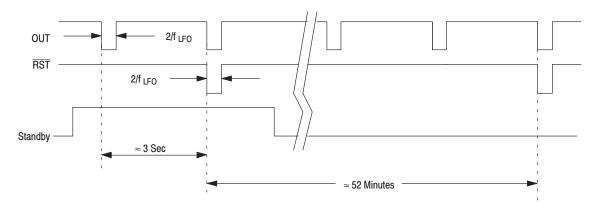


Figure 5. Pulse on RST Pin

### S0 Pin

The S0 pin is used to select the mode of operation as shown in Table 1.

The S0 pin contains an internal Schmitt trigger as part of its input to improve noise immunity. The S0 pin has an internal pull–down device in order to provide a low level when the pin is left unconnected.

### S1 Pin

The S1 pin is used to select the mode of operation, as shown in Table 1.

The S1 pin contains an internal Schmitt trigger as part of its input to improve noise immunity. This pin has an internal pulldown device to provide a low level when the pin is left unconnected.

The S1 pin also serves the purpose of enabling factory trim and test of the device.

The higher V<sub>PP</sub> programming voltage for the internal EE-PROM trim register is also supplied through the S1 pin.

#### DATA Pin

The DATA pin is the serial data in (SDI) function for setting the threshold of the voltage comparator.

The DATA pin contains an internal Schmitt trigger as part of its input to improve noise immunity. This pin has an internal pull-down device to provide a low level when the pin is left unconnected.

#### **CLK Pin**

The CLK pin is used to provide a clock used for loading and shifting data into the DATA pin. The data on the DATA pin is clocked into a shift register on the rising edge of the CLK pin signal. The data is transferred to the D/A Register on the eighth falling edge of the CLK pin. This protocol may be handled by the SPI or SIOP serial I/O function found on some MCU devices.

The CLK pin contains an internal Schmitt trigger as part of its input to improve noise immunity. The CLK pin has an internal pulldown device to provide a low level when the pin is left unconnected.

#### **Output Threshold Adjust**

The state of the OUT pin is driven by a voltage comparator whose output state depends on the level of the input voltage on the sample capacitor and the level of an adjustable 8-bit threshold voltage. The threshold is adjusted by shifting data bits into the D/A Register (DAR) via the DATA pin while clocking the CLK pin. The timing of this data is shown in Figure 6. Data is transferred into the serial shift register on the

rising edge of the CLK pin. On the falling edge of the 8th clock the data in the serial shift register is latched into the parallel DAR register. The DAR remains powered up whenever  $V_{DD}$  is present. The serial data is clocked into the DATA pin starting with the MSB first. This sequence of threshold select bits is shown in Table 2.

**Bit Weight Function Data Bit** LSB D0 1 2 D1 4 D2 8 D3 Voltage Comparator Threshold Adjust (8 bits) 16 D4 32 D5 64 D6

Table 2. D/A Threshold Bit Assignments

**MSB** 

128

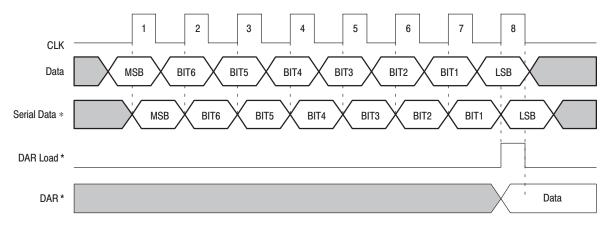
An analog to digital (A/D) conversion can be accomplished with eight (8) different threshold levels in a successive approximation algorithm; or the OUT pin can be set to trip at some alarm level. The voltage on the sample capacitor will maintain long enough for a single 8–bit conversion, but may need to be refreshed with a new measured reading if the read interval is longer than the specified hold time,  $t_{SH}$ .

The counter that determines the number of clock pulses into the device is reset whenever the device is placed into the Measure Pressure or Measure Temperature Modes. This provides a means to reset the data transfer count in case the

clock stream is corrupted during a transmission. In these two modes the DATA and CLK pins should not be clocked to reduce noise in the captured pressure or temperature data. Any change in the DAR contents should be done during the Standby or Output Read Modes.

D7

Both the serial bit counter and the state of the DAR are undefined following power up of the device. The serial bit counter can be reset by cycling either the SO pin or the S1 pin to a high level and then back low. The DAR can then be reset to the lowest level by holding the DATA pin low while bursting the CLK pin with eight (8) clock pulses.



(\*) Denotes Internal Signal

Figure 6. Serial Data Timing

#### Pressure Sensor Output

The pressure channel compares the output of its analog measurement circuit to the D/A reference voltage. The device is calibrated at two different nominal values depending on the calibration option.

#### Temperature Sensor Output

The temperature channel compares the output of a positive temperature coefficient (PTC) resistor driven by a switched current source. The current source is only active when the temperature channel is selected.

#### **APPLICATIONS**

Suggested application example is shown in Figure 7.

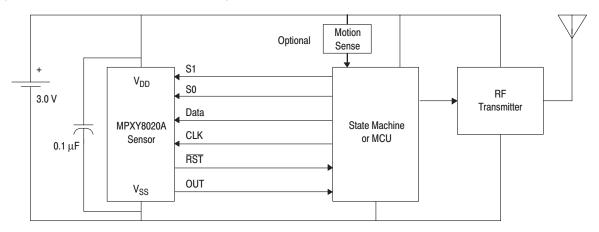


Figure 7. Application Example

#### **ELECTRICAL SPECIFICATIONS**

## **Maximum Ratings**

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Maximum ratings are the extreme limits to which the device can be exposed without permanently damaging it. The device contains circuitry to protect the inputs against damage from high static voltages; however, do not apply voltages higher than those shown in the table below. Keep  $V_{IN}$  and  $V_{OUT}$  within the range  $V_{SS} \le (V_{IN} \text{ or } V_{OUT}) \le V_{DD}$ .

Rating	Symbol	Value	Unit
Supply Voltage	V <sub>DD</sub>	-0.3 to +4.0	V
Short Circuit Capability (all pins excluding V <sub>DD</sub> and V <sub>SS</sub> )  Maximum High Voltage for 5 minutes  Minimum Low Voltage for 5 minutes	V <sub>SC</sub> V <sub>SC</sub>	V <sub>DD</sub> V <sub>SS</sub>	V
Substrate Current Injection Current from any pin to V <sub>SS</sub> – 0.3 VDC)	I <sub>SUB</sub>	600	μА
Electrostatic Discharge Human Body Model (HBM) Charged Device Model (CDM) Machine Model (MM)	V <sub>ESD</sub> V <sub>ESD</sub> V <sub>ESD</sub>	±1000 ±1000 ±200	V V V
Storage Temperature Range Standard Temperature Range	T <sub>stg</sub>	-40 to +150	°C

Operating Range
The limits normally expected in the application which define range of operation.

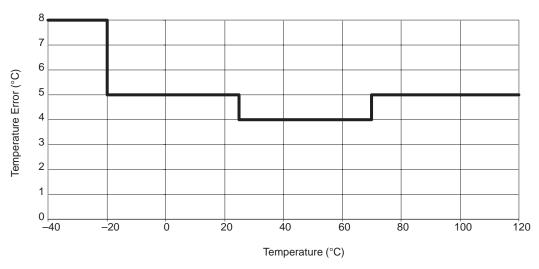
Characteristic	Symbol	Min	Тур	Max	Units
Supply Voltage	$V_{DD}$	2.1	3.0	3.6	V
Operating Temperature Range Standard Temperature Range	T <sub>A</sub>	T <sub>L</sub> -40	_	T <sub>H</sub> +125	°C
Supply Current Drain  Standby Mode  -40°C to +85°C  +85°C to +100°C  +100°C to +125°C  Read Mode  -40°C to +125°C  Measure Temperature Mode  -40°C to +125°C  Measure Pressure Mode  -40°C to +10°C  +10°C to +60°C  +60°C to +125°C	I <sub>stby</sub> I <sub>stby</sub> I <sub>stby</sub> I <sub>read</sub> I <sub>temp</sub> I <sub>press</sub> I <sub>press</sub> I <sub>press</sub>	- - -	0.6 0.8 1.5 400 400 1400 1300 1200	0.9 1.2 2.2 600 600 1800 1700 1700	µА µА µА µА µА µА

## **Electrical Characteristics**

+2.1 V  $\leq$  V<sub>DD</sub>  $\leq$  +3.6 V, T<sub>L</sub>  $\leq$  T<sub>A</sub>  $\leq$  T<sub>H</sub>, unless otherwise specified.

Characteristic	Symbol	Min	Тур	Max	Units
Output High Voltage DATA, OUT, RST (I <sub>Load</sub> = 100 μA)	V <sub>OH</sub>	V <sub>DD</sub> -0.8	_	_	V
Output Low Voltage DATA, OUT, $\overline{RST}$ (I <sub>Load</sub> = -100 $\mu$ A)	V <sub>OL</sub>	_	_	0.4	V
Input High Voltage S1, S0, DATA, CLK	V <sub>IH</sub>	0.7 x V <sub>DD</sub>	_	_	V
Input Low Voltage S1, S0, DATA, CLK	V <sub>IL</sub>	V <sub>SS</sub>	_	0.3 x V <sub>DD</sub>	V
Input Hysteresis (V <sub>IH</sub> – V <sub>IL</sub> ) S1, S0, DATA, CLK	V <sub>HYS</sub>	100	200	_	mV
Input Low Current (at V <sub>IL</sub> ) S1, S0, DATA, CLK	I <sub>IL</sub>	-5	-25	-100	μА
Input High Current (at V <sub>IH</sub> ) S1, S0, DATA, CLK	I <sub>IH</sub>	-5	-35	-140	μА
Temperature Measurement (+2.5V≤Vdd≤3.0V) D/A Conversion Code at −40°C D/A Conversion Code at −20°C D/A Conversion Code at 25°C D/A Conversion Code at 70°C D/A Conversion Code at 100°C D/A Conversion Code at 120°C D/A Conversion Code at 125°C	T <sub>-40</sub> T <sub>-20</sub> T <sub>25</sub> T <sub>70</sub> T <sub>100</sub> T <sub>120</sub> T <sub>125</sub>	36 52 97 155 204 241 249	42 57 102 163 214 252 255	47 62 107 171 224 255 255	counts counts counts counts counts counts counts counts counts
Temperature Measurement (+2.1V≤Vdd≤3.6V) D/A Conversion Code at −40°C D/A Conversion Code at −20°C D/A Conversion Code at 25°C D/A Conversion Code at 70°C D/A Conversion Code at 100°C D/A Conversion Code at 120°C D/A Conversion Code at 125°C	T <sub>-40</sub> T <sub>-20</sub> T <sub>25</sub> T <sub>70</sub> T <sub>100</sub> T <sub>120</sub> T <sub>125</sub>	36 52 97 154 203 240 249	42 57 102 163 214 252 255	49 64 107 172 225 255 255	counts counts counts counts counts counts counts counts
Temperature Sensitivity at 25°C		_	0.80	_	°C/bit
Approximate Temperature Output Response	OUT = 7	74.7461 +0.975	52 x Ta + 0.004	1 x Ta^2	counts

## Temperature Error vs. Temperature ( $V_{DD} = 3 V$ )



Characteristic	Symbol	Min	Тур	Max	Units
HFO Measurement Clock Frequency	f <sub>HF</sub>	100	135	150	kHz
LFO Wake Up Clock Frequency $Ta = -40^{\circ}C$ , +2.1V $\leq$ Vdd $\leq$ +3.6 $Ta = +25^{\circ}C$ , +2.1V $\leq$ Vdd $\leq$ +3.6 $Ta = +125^{\circ}C$ , +2.1V $\leq$ Vdd $\leq$ +3.6	f <sub>LF</sub> f <sub>LF</sub>	3300 3900 3800	5400 5400 5300	8000 7700 7000	Hz Hz Hz
Wake Up Pulse Pulse Timing Pulse Width	t <sub>WAKE</sub>	_ _	16384 2	_ _	LFO clocks LFO clocks
Reset Pulse Pulse Timing Pulse Width	t <sub>RESET</sub>	_ _	16,777,216 2		LFO clocks LFO clocks
Minimum Setup Time (DATA edge to CLK rise)	t <sub>SETUP</sub>	100	_		nSec
Minimum Hold Time (CLK rise to DATA change)	tHOLD	100	_	_	nSec
Measurement Response Time Recommended time to hold device in measurement mode Temperature Pressure	t <sub>TMEAS</sub>		200 500		μSec μSec
Read Response Time (see Figure 8) From 90% V <sub>DD</sub> on S0 To OUT less than V <sub>OL</sub> or greater than V <sub>OH</sub>	t <sub>READ</sub>	_	50	100	μSec
Sample Capacitor Discharge Time From initial full scale D/A count (255) to drop 2 counts (253)	tsн	20	_	_	mSec

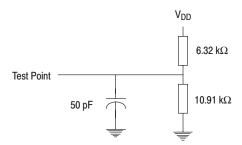


Figure 8. Control Timing Test Load for OUT and  $\overline{\mbox{RST}}$  Pins

## **SENSOR CHARACTERISTICS (MPXY8020A)**

#### **Pressure Transfer Function**

kPa =  $2.5 \times \text{Output} \pm \text{(Pressure Error)}$ 

Output = 8-bit digital pressure measurement (between 0-255)

## Pressure Error ( $\pm$ kPa): 50 kPa $\leq$ P < 250 kPa

T[°C] \ V <sub>DD</sub> [V]	2.1	2.5	2.7	3.0	3.3	3.6
-40	72.5	72.5	32.5	32.5	32.5	35.0
-20	57.5	57.5	25.0	25.0	25.0	27.5
0	57.5	57.5	25.0	25.0	25.0	27.5
25	57.5	57.5	25.0	25.0	25.0	27.5
70	57.5	57.5	27.5	25.0	25.0	27.5
100	72.5	72.5	37.5	37.5	37.5	37.5
125	95.0	92.5	57.5	47.5	47.5	47.5

## Pressure Error ( $\pm$ kPa): 250 kPa $\leq$ P $\leq$ 450 kPa

T[°C] \ V <sub>DD</sub> [V]	2.1	2.5	2.7	3.0	3.3	3.6
-40	40.0	40.0	25.0	25.0	25.0	30.0
-20	32.5	25.0	15.0	15.0	15.0	20.0
0	30.0	25.0	10.0	10.0	10.0	15.0
25	30.0	25.0	7.5	7.5	7.5	15.0
70	35.0	25.0	10.0	7.5	7.5	15.0
100	40.0	40.0	25.0	25.0	25.0	30.0
125	62.5	60.0	35.0	35.0	35.0	35.0

## Pressure Error ( $\pm$ kPa): 450 kPa < P $\leq$ 600 kPa

T[°C] \ V <sub>DD</sub> [V]	2.1	2.5	2.7	3.0	3.3	3.6
-40	70.0	70.0	37.5	37.5	37.5	40.0
-20	55.0	55.0	25.0	25.0	25.0	35.0
0	55.0	55.0	22.5	22.5	22.5	35.0
25	55.0	55.0	22.5	22.5	22.5	35.0
70	55.0	55.0	25.0	25.0	25.0	35.0
100	70.0	70.0	32.5	32.5	32.5	40.0
125	90.0	90.0	47.5	47.5	47.5	52.5

Areas marked in grey indicate the typical operating range.

## SENSOR CHARACTERISTICS (MPXY8020A)

#### **Pressure Error**

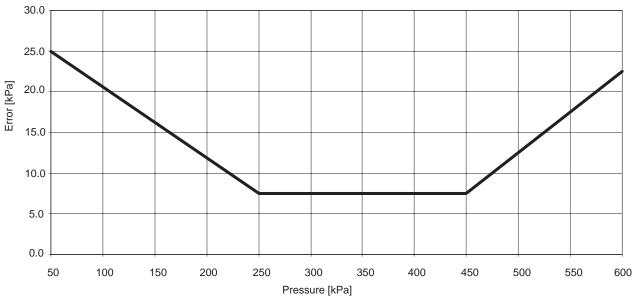


Figure 9. Pressure Error vs Pressure at T= 25°C, 2.7  $\leq$  V<sub>DD</sub>  $\leq$  +3.3 V

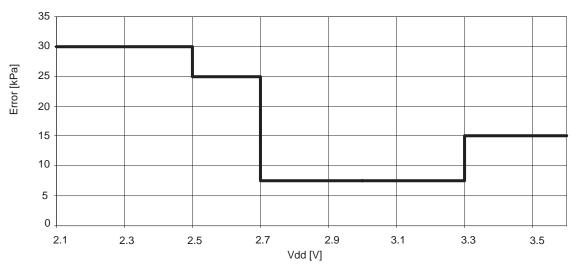


Figure 10. Pressure Error vs  $V_{DD}$  at 25°C, 250 kPa  $\leq$  P  $\leq$  450 kPa

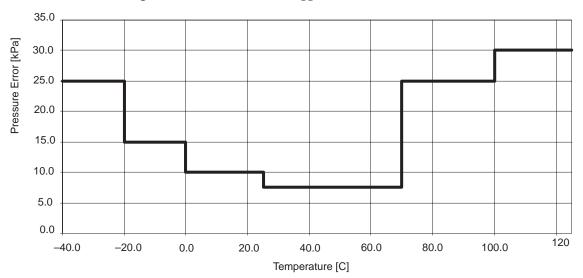


Figure 11. Pressure Error vs. Temperature at  $V_{DD}$  = 3 V, 250 kPa  $\leq$  P  $\leq$  450 kPa

## **MECHANICAL SPECIFICATIONS**

#### **Maximum Ratings**

Maximum ratings are the extreme limits to which the device can be exposed without permanently damaging it. Keep  $V_{IN}$  and  $V_{OUT}$  within the range  $V_{SS} \le (V_{IN} \text{ or } V_{OUT}) \le V_{DD}$ .

Rating	Symbol	Value	Unit
Maximum Pressure (1)	p <sub>max</sub>	1400	kPa <sup>(1)</sup>
Centrifugal Force Effects (3 axis) Pressure measurement change less than 1% FSS	9cent	2000	g
Unpowered Shock (three sides, 0.5 mSec duration)	9shock	2000	g

#### NOTES:

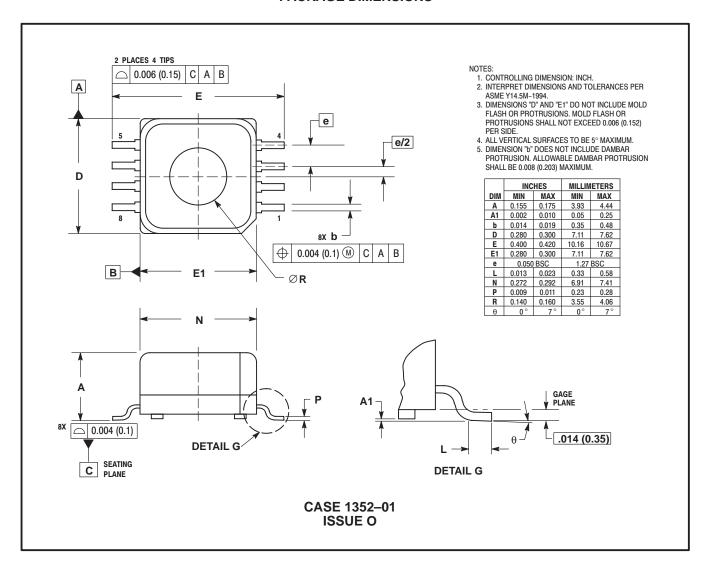
1. Tested for 5 min at 25°C

#### **Media Compatibility**

Media compatibility is as specified in Motorola document "SPD TPM Media Test."

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#### PACKAGE DIMENSIONS



# **NOTES**

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